

深圳维盛半导体科技有限公司 VS11K09A-1 IC手册参考





1 PRODUCT OVERVIEW

1.1 FEATURES

Memory configuration

Flash ROM size: 64KB.

User RAM: 8KB.

USB FIFO RAM: 256 bytes.

♦ Operation Frequency up to 48MHz

♦ Interrupt sources

ARM Cortex-M0 built-in Nested Vectored Interrupt

Controller (NVIC).

♦ I/O pin configuration

Bi-directional: P0, P1, P2, P3.

Wakeup: P0, P1, P2, P3 level change.

Pull-up resisters: P0, P1, P2, P3.

20mA Sink/10mA Drive: P0, P1, P2, P3.

♦ Programmable WatchDog Timer (WDT)

Programmable watchdog frequency with watchdog clock source and divider.

System tick timer

24-bit timer.

The system tick timer clock is fixed to the frequency of the system clock.

The SysTick timer is intended to generate a fixed 10-ms interrupt.

LVD with separate thresholds

Reset: 1.65V for V_{CORE} 1.8V.

Reset: 2.4V/2.7V/3.0V/3.6V for VDD. Interrupt: 2.4V/2.7V/3.0V/3.6V for VDD.

◆ Full Speed USB 2.0

3.3v regulator output for D+ internal 1.5k pull-up resistor.

Supports one Full speed USB device address. Supports PS/2 mode.

One control EP and 4 configurable INT/BULK Endpoints.

EP0 supports 64-byte FIFO depth.

Programmable EP1~EP4 FIFO depth.

Total 5 endpoints share 256-byte USB RAM.

Working voltage 2.5V ~ 5.5V

◆ Timer

One 16-bit general purpose timer CT16B0 with CAP0. One 16-bit general purpose timer CT16B1 with 24-ch PWM.

♦ Interfaces

- One I2C controller supporting I2C-bus specification.
- One SPI controller supporting SPI protocol.
- Three UART controller with fractional baud rate generation

♦ 16+1-ch 12-bit SAR ADC with 4-level Int. Ref. Voltage

- -16-ch external ADC input.
- -1-ch battery measurement.
- -4-level internal reference voltage source.(VDD, 4.5V, 3V, 2V)

System clocks

Internal high clock: RC type 48MHz. Internal low clock: RC type 32KHz.

♦ Serial Wire Debug (SWD)

Operating modes

Normal, Sleep, and Deep-sleep.

♦ Fcpu (Instruction cycle)

F_{CPU} = F_{HCLK} = F_{SYSCLK}/1, F_{SYSCLK}/2, F_{SYSCLK}/4, ..., F_{SYSCLK} /128.

In-System-Programming (ISP) supported

♦ 3.3V Regulator output

Driving current 60mA

Power for USB D+ internal pull-up resistor.

Can be IO power for P0.0~P0.7. (3.3V IOs)

Can be power source for peripheral 3.3V devices.

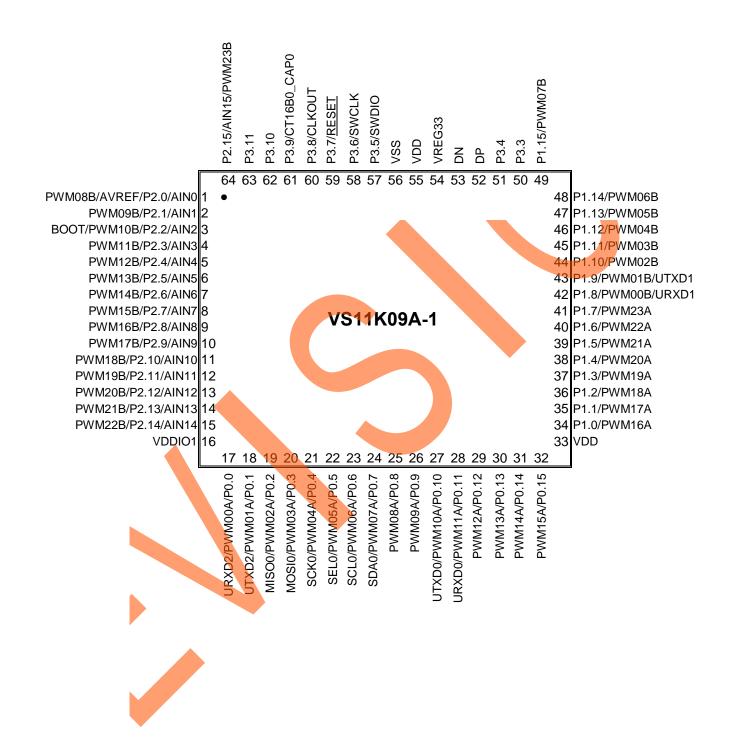
♦ Package (Chip form support)

LQFP64 pin



1.2 PIN ASSIGNMENT

VS11K09A-1 (LQFP 64 pins)





2 USB FS DEVICE INTERFACE

2.1 OVERVIEW

The USB is the answer to connectivity for the PC architecture. A fast, bi-directional interrupt pipe, low-cost, dynamically attachable serial interface is consistent with the requirements of the PC platform of today and tomorrow. The USB microcontrollers are optimized for human-interface computer peripherals such as a mouse, keyboard, joystick, and game pad.

USB Specification Compliance

- Conforms to USB specifications, Version 2.0.
- Supports 1 Full-speed USB device address.
- Supports 1 control endpoint and 4 configurable endpoints for interrupt/bulk transfer.
- Integrated USB transceiver.
- 5V to 3.3V regulator output for D+ 1.5K ohm internal resistor pull up.

2.2 FEATURES

- Conforms to USB specifications, Version 2.0.
- Supports 1 Full-speed USB device address.
- Supports 1 control endpoint with maximum packet size 8 bytes, 16 bytes, 32 bytes, or 64 bytes.
- Supports 4 endpoints configurable for interrupt/bulk transfer.
- Supports USB SRAM size 256 bytes shared by all 5 endpoints.
- Flexible data FIFO offset setting for endpoints except endpoint 0.
- > 5V to 3.3V regulator output for D+ 1.5K ohm internal resistor pull up.
- Integrated USB transceiver.
- FS USB function work under system clock SYSCLK/1, SYSCLK/2, SYSCLK/4.

2.3 PIN DESCRIPTION

Pin Name	Туре	Description	GPIO Configuration
DP	I/O	USB differential signal D+	N/A
DN	I/O	USB differential signal D-	N/A



3 FLASH

3.1 OVERVIEW

32-bit MCU integrated device feature in-system programmable (ISP) FLASH memory for convenient, upgradeable code storage. The FLASH memory may be programmed via the 32-bit MCU programming interface or by application code for maximum flexibility. 32-bit MCU provides security options at the disposal of the designer to prevent unauthorized access to information stored in FLASH memory.

- > The MCU is stalled during Flash program and erase operations, although peripherals (Timers, WDT, I/O, PWM, etc.) remain active.
- Watchdog timer should be cleared if enabled before the Flash write or erase operation.
- The erase operation sets all the bits in the Flash page to logic 0.
- HW will hold system clock and automatically move out data from RAM and do programming, after programming finished, HW will release system clock and let MCU execute the next instruction.

3.2 EMBEDDED FLASH MEMORY

The Flash memory is organized as 32-bit wide memory cells that can be used for storing both code and data constants, and is located at a specific base address in the memory map of chip.

The high-performance Flash memory module in chip has the following key features:

Memory organization: the Flash memory is organized as a User ROM.

User ROM	Up to 16K x 32 bits divided into 1024 pages of 64 Bytes
Boot ROM	Up to 768 x 32 bits divided into 48 pages of 64 Bytes

The Flash interface implements instruction access and data access based on the AHB protocol. It implements the logic necessary to carry out Flash memory operations (Program/Erase). Program/Erase operations can be performed over the whole product voltage range.

3.3 FEATURES

- Read interface (32-bit)
- Flash Program / Erase operation
- Code Option includes Code Security (CS)

Write operations to the main memory block and the code options are managed by an embedded Flash Memory Controller (FMC). The high voltage needed for Program/Erase operations is internally generated. The main Flash memory can be read/write protected against different levels of Code Security (CS).

During a write operation to the Flash memory, any attempt to read the Flash memory will stall the bus. The read operation will proceed correctly once the write operation has completed. This means that code or data fetches cannot be made while a write/erase operation is ongoing.

For write and erase operations on the Flash memory, the IHRC will be turn ON by FMC. The Flash memory can be programmed and erased using ICP and ISP.



3.4 ORGANIZATION

Blo	ck	Name	Base Address	Size (Byte)
		Page 0	0x00000000 ~ 0x0000003F	64
		Page 1	0x00000040 ~ 0x0000007F	64
	User ROM			
	64KB		•	
		•	•	
VS11K09A-1		Page 1022	0x0000FF80 ~ 0x0000FFBF	64
ROM		Page 1023	0x0000FFC0 ~ 0x0000FFFF	64
		Page 0	0x1FFF0000 ~ 0x1FFF003F	64
	Boot Loader			
	3KB	•	•	•
				•
		Page 47	0x1FFF0BC0 ~ 0x1FFF0BFF	64

3.5 READ

The embedded Flash module can be addressed directly, as a common memory space. Any data read operation accesses the content of the Flash module through dedicated read senses and provides the requested data.

The read interface consists of a read controller on one side to access the Flash memory, and an AHB interface on the other side to interface with the CPU. The main task of the read interface is to generate the control signals to read from the Flash memory as required by the CPU.

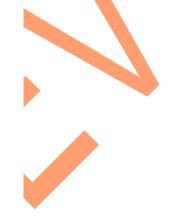
3.6 PROGRAM/ERASE

The Flash memory erase operation can be performed at page level.

To ensure that there is no over-programming, the Flash programming and erase controller blocks are clocked by IHRC.

3.7 EMBEDDED BOOT LOADER

The embedded boot loader is used to reprogram the Flash memory using the USB interface.





4

ELECTRICAL CHARACTERISTIC

4.1 ABSOLUTE MAXIMUM RATING

Supply voltage (Vdd)... $-0.3V \sim 5.5V$ Input in voltage (Vin)... $Vss - 0.2V \sim Vdd + 0.2V$ Operating ambient temperature (Topr). $-40^{\circ}\text{C} \sim +85^{\circ}\text{C}$ Storage ambient temperature (Tstor) $-40^{\circ}\text{C} \sim +125^{\circ}\text{C}$

4.2 ELECTRICAL CHARACTERISTIC

Voltage	MIN.	TYP.	MAX.	UNIT
Voltage	2.5	3.3	5.5	V
Idd1	3.1	5.0	5.25	V
Idd1	0.05	-	-	V/ms
Idd1 Normal mode				
Idd1 Normal mode		3.8	-	mA
Idd2 Sleep Mode System clock = 32KHz Idd3 Deep-sleep Mode Vdd=5V Idd5 Idd3 Deep-sleep Mode Vdd=5V Idd5 Idd5 Deep-sleep Mode Vdd=5V Idd5 Id	-	11	-	mA
Idd2 Sleep Mode Vid=5V It It It It It It It I	-	14	-	mA
Idd3 Deep-sleep Mode I1 5	-	200	-	uA
High-level input voltage	-	1	-	uA
Low-level input voltage Vi			T	
Input voltage).7Vdd	-	Vdd	V
Output voltage	Vss	-	0.3Vdd	V
Vin = Vss , Vdd = 5.0V	0	-	Vdd	V
I/O port pull-up resistor Vin = Vss , Vdd = 3.3V I/O High-level output source current O Low-level output sink current IoL VoP = Vdd - 0.5V; ADC ADC ADC ADC ADC ADC ADC Operating Voltage ADC reference Voltage *ADC enable time *ADC current consumption ADC *ADC current consumption ADC *ADC Clock Frequency ADC Clock Frequency ADC Conversion Cycle Time ADC Sampling Rate FADCYL ADC Sampling Rate FADSMP Vdd=3.3V Differential Nonlinearity INL Vdd=5.5V , AVREFH=2.4V Integral Nonlinearity No Missing Code NMC Vdd=5.5V , AVREFH=2.4V Integral Nonlinearity INL Vdd=5.5V , AVREFH=2.4V	0	-	Vdd	V
Vin = Vss , Vdd = 3.3V Start	30	50	70	ΚΩ
Current O Low-level output sink current IoL VoP = Vss + 0.5V ADC ADC ADC ADC ADC ADC ADC AD	50	75	100	ΚΩ
ADC Operating Voltage VADC 2 AINO ~ AIN15 input voltage Vani Voltage	6	10	-	mA
ADC Operating Voltage AIN0 ~ AIN15 input voltage ADC reference Voltage *ADC enable time *ADC current consumption ADC Clock Frequency ADC Conversion Cycle Time ADC Sampling Rate FADSMP Differential Nonlinearity INL Vdd=5.5V , AVREFH=2.4V No Missing Code AIN15 input voltage Vani ADC Vani ADC voltage Vref ABC start convert after set ADENB = "1" 1 *ADC vdd=3.3V, ADS=0 *ADC Sampling Rate FADCYL Vdd=3.3V FADCYL Vdd=3.3V ADC Sampling Rate FADSMP Vdd=3.3V Vdd=5.5V , AVREFH=2.4V AVREFH=2.4V No Missing Code NMC Vdd=5.5V , AVREFH=2.4V	12	20	-	mA
AIN0 ~ AIN15 input voltage V _{ani} ADC reference Voltage V _{ref} *ADC enable time T _{ast} Ready to start convert after set ADENB = "1" 1 *ADC current consumption I _{ADC} Vdd=3.3V, ADS=0 ADC Clock Frequency F _{ADCLK} Vdd=3.3V ADC Conversion Cycle Time F _{ADCYL} VDD=2.5V~5.5V 6 ADC Sampling Rate F _{ADSMP} Vdd=3.3V Differential Nonlinearity DNL Vdd=5.5V , AVREFH=2.4V				
ADC reference Voltage V _{ref} 2 *ADC enable time T _{ast} Ready to start convert after set ADENB = "1" 1 *ADC current consumption I _{ADC} Vdd=3.3V, ADS=0 ADC Clock Frequency F _{ADCLK} Vdd=3.3V ADC Conversion Cycle Time F _{ADCYL} VDD=2.5V~5.5V 6 ADC Sampling Rate F _{ADSMP} Vdd=3.3V Differential Nonlinearity DNL Vdd=5.5V, AVREFH=2.4V - Integral Nonlinearity INL Vdd=5.5V, AVREFH=2.4V - No Missing Code NMC Vdd=5.5V, AVREFH=2.4V -	2.5		5.5	V
*ADC enable time T _{ast} Ready to start convert after set ADENB = "1" 1 *ADC current consumption I _{ADC} Vdd=3.3V, ADS=0 ADC Clock Frequency F _{ADCLK} Vdd=3.3V ADC Conversion Cycle Time F _{ADCYL} VDD=2.5V~5.5V ADC Sampling Rate F _{ADSMP} Vdd=3.3V Differential Nonlinearity DNL Vdd=5.5V , AVREFH=2.4V Integral Nonlinearity INL Vdd=5.5V , AVREFH=2.4V No Missing Code NMC Vdd=5.5V , AVREFH=2.4V	0	-	Avrefh	>
*ADC current consumption I _{ADC} Vdd=3.3V, ADS=0 ADC Clock Frequency F _{ADCLK} Vdd=3.3V ADC Conversion Cycle Time F _{ADCYL} VDD=2.5V~5.5V ADC Sampling Rate F _{ADSMP} Vdd=3.3V Differential Nonlinearity DNL Vdd=5.5V , AVREFH=2.4V Integral Nonlinearity INL Vdd=5.5V , AVREFH=2.4V No Missing Code NMC Vdd=5.5V , AVREFH=2.4V	2.5	-	-	V
ADC Clock Frequency FADCLK Vdd=3.3V ADC Conversion Cycle Time FADCYL VDD=2.5V~5.5V 6 ADC Sampling Rate FADSMP Vdd=3.3V Differential Nonlinearity DNL Vdd=5.5V , AVREFH=2.4V - Integral Nonlinearity INL Vdd=5.5V , AVREFH=2.4V - No Missing Code NMC Vdd=5.5V , AVREFH=2.4V -	100	-	-	us
ADC Conversion Cycle Time FADCYL VDD=2.5V~5.5V 6 ADC Sampling Rate FADSMP Vdd=3.3V Differential Nonlinearity DNL Vdd=5.5V , AVREFH=2.4V Integral Nonlinearity INL Vdd=5.5V , AVREFH=2.4V No Missing Code NMC Vdd=5.5V , AVREFH=2.4V	-	100*	-	uA
ADC Conversion Cycle Time FADCYL VDD=2.5V~5.5V 6 ADC Sampling Rate FADSMP Vdd=3.3V Differential Nonlinearity DNL Vdd=5.5V , AVREFH=2.4V Integral Nonlinearity INL Vdd=5.5V , AVREFH=2.4V No Missing Code NMC Vdd=5.5V , AVREFH=2.4V	-	-	16	MH
Differential Nonlinearity Integral Nonlinearity No Missing Code DNL Vdd=5.5V , AVREFH=2.4V Vdd=5.5V , AVREFH=2.4V NO Missing Code NMC Vdd=5.5V , AVREFH=2.4V	64	-	-	1/FADO
Integral Nonlinearity INL Vdd=5.5V , AVREFH=2.4V No Missing Code NMC Vdd=5.5V , AVREFH=2.4V		-	250	KHz
No Missing Code NMC Vdd=5.5V , AVREFH=2.4V	-1	-	+1	LSE
	-1	-	+1	LSE
ADC offset Voltage VADCoffset	10	-	12	Bits
	-5		+5	m∨
FLASH Endurance time T _{EN} Erase + Program 11	10K	*100K		Cycl



VS 32-Bit Cortex-M0 Micro-Controller

Page erase time	T_ME	All User ROM memory.	-	5	-	ms	
Page Programming time	T_{PG}	1 -Page (64 bytes).	-	5	-	ms	
MISC							
			Level 0	-	2.40	-	V
Low Voltage Detector	LVD	Interrupt/Reset	Level 1	-	2.70	-	V
			Level 2	-	3.00	-	V
			Level 3	1	3.60	-	V
3.3V Regulator Output voltage	V_{REG33}	$VCC \ge 3.60V$, $IVREG33 \le 60 \text{ mA}$	3.0		3.4	V	
IHRC Freq.	F _{IHRC}	T=25°C, Vdd=5V, USB function ON			48	48.12	MHz

* Parameters with star mark are non-verified design reference.

- [1] IDD measurements were performed with all pins configured as GPIO outputs driven LOW and pull-up resistors disabled and VDD=5V.
- [2] IHRC and ILRC are enabled.
- [3] LVD and GPIO peripherals are enabled.
- [4] IHRC is disabled, ILRC is enabled.[5] All oscillators and analog blocks are turned off.

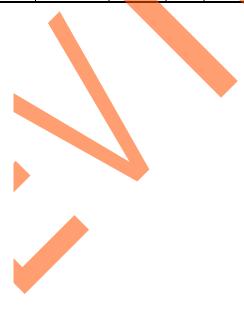




5

FLASH ROM PROGRAMMING PIN

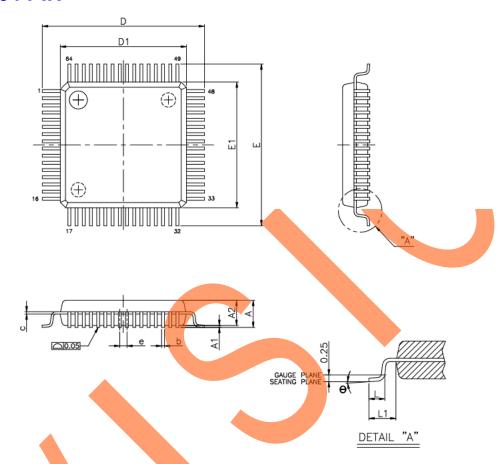
	Programming Information							
Chi	Name	VS11K0						
MP PRO Writer Connector		Flash IC / JP3 Pin Assignment						
Number	Name	Number	Pin					
1	VDD	55	VDD					
2	GND	56	VSS					
3	CLK	61	P3.9					
4	CE							
5	PGM	58	P3.6					
6	OE	57	P3.5					
7	D1							
8	D0							
9	D3							
10	D2							
11	D5							
12	D4							
13	D7							
14	D6							
15	VDD							
16	-							
17	HLS							
18	RST							
19	-							
20	ALSB/PDB	60	P3.8					





6 PACKAGE INFORMATION

6.1 LQFP 64 PIN



VARIATIONS (ALL DIMENSIONS SHOWN IN MM)

SYMBOLS	MIN.	NOM.	MAX.			
Α	1	-	1.60			
A1	0.05	_	0.15			
A2	1.35	1.40	1.45			
Ф	0.13	0.18	0.23			
С	0.09 - 0.2					
D	9.00 BSC					
D1	7.00 BSC					
е	0.40 BSC					
E	9.00 BSC					
E1	7.00 BSC					
L	0.45 0.60 0.75					
L1	1.00 REF					
θ	0° 3.5° 7°					